Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/801,537	QIN, CHUNLAN
Examiner	Art Unit
Erin M. File	2611

SEARCHED				
Class	Subclass	Date	Examiner	
375	344	4/8/2007	EMF	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH S)
	DATE	EXMR
EAST US PAT, USPGPUB, EPO, JPO DERWENT, IBM (text search only—see search history printout)	4/8/2007	EMF
PALM INVENTORSHIP	4/8/2007	EMF
PLUS Search	4/9/2007	EMF
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